Test Report

No.: EKR24600524 Date: 18-Jun-2024

NXP SEMICONDUCTORS
HIGH TECH CAMPUS 60, 5656AG EINDHOVEN, THE NETHERLANDS

The following sample(s) was/were submitted and identified by the applicant as:

Sample Submitted By : NXP SEMICONDUCTORS NETHERLANDS B.V.
Sample Name : CHANDLER BARE WAFER

==========

Sample Receiving Date : 11-Jun-2024
Testing Period : 11-Jun-2024 to 18-Jun-2024

Test Requested :
(1) As specified by client, with reference to RoHS 2011/65/EU Annex II and amending Directive (EU) 2015/863 to determine Cadmium, Lead, Mercury, Cr(VI), PBBs, PBDEs, DBP, BBP, DEHP, DIBP contents in the submitted sample(s).
(2) Please refer to next pages for the other item(s).

Test Results : Please refer to following pages.

Conclusion :
(1) Based on the performed tests on submitted sample(s), the test results of Cadmium, Lead, Mercury, Cr(VI), PBBs, PBDEs, DBP, BBP, DEHP, DIBP comply with the limits as set by RoHS Directive (EU) 2015/863 amending Annex II to Directive 2011/65/EU.

Ray Chang, Ph.D./Department Manager
Signed for and on behalf of
SGS TAIWAN LTD.
Chemical Laboratory-Kaohsiung

PIN CODE: D1BACA24

This document is issued by the Company subject to its General Conditions of Service printed overleaf, available on request or accessible at https://www.sgs.com.tw/terms-of-service and, for electronic format documents, subject to Terms and Conditions for Electronic Documents at https://www.sgs.com.tw/terms-of-service. Attention is drawn to the limitation of liability, indemnification and jurisdiction issues defined therein. Any holder of this document is advised that information contained hereon reflects the Company's findings at the time of its intervention only and within the limits of client's instruction, if any. The Company's sole responsibility is to its Client and this document does not exonerate parties to a transaction from exercising all their rights and obligations under the transaction documents. This document cannot be reproduced, except in full, without prior written approval of the Company. Any unauthorized alteration, forgery or falsification of the content or appearance of this document is unlawful and offenders may be prosecuted to the fullest extent of the law. Unless otherwise stated the results shown in this test report refer only to the sample(s) tested.

NXP SEMICONDUCTORS
HIGH TECH CAMPUS 60, 5656AG EINDHOVEN, THE NETHERLANDS

Test Part Description

No.1 : WAFER

Test Result(s)

Test Item(s)	Method	Unit	MDL	Result No.1	Limit
Cadmium (Cd)	With reference to IEC 62321-5: 2013, analysis was performed by ICP-OES.	mg/kg	2	n.d.	100
Lead (Pb)		mg/kg	2	n.d.	1000
Mercury (Hg)	With reference to IEC 62321-4: 2013+ AMD1: 2017, analysis was performed by ICP-OES.	mg/kg	2	n.d.	1000
Hexavalent Chromium Cr(VI)	With reference to IEC 62321-7-2: 2017, analysis was performed by UV-VIS.	mg/kg	8	n.d.	1000
Monobromobiphenyl	With reference to IEC 62321-6: 2015, analysis was performed by GC/MS.	mg/kg	5	n.d.	-
Dibromobiphenyl		mg/kg	5	n.d.	-
Tribromobiphenyl		mg/kg	5	n.d.	-
Tetrabromobiphenyl		mg/kg	5	n.d.	-
Pentabromobiphenyl		mg/kg	5	n.d.	-
Hexabromobiphenyl		mg/kg	5	n.d.	-
Heptabromobiphenyl		mg/kg	5	n.d.	-
Octabromobiphenyl		mg/kg	5	n.d.	-
Nonabromobiphenyl		mg/kg	5	n.d.	-
Decabromobiphenyl		mg/kg	5	n.d.	-
Sum of PBBs		mg/kg	-	n.d.	1000
Monobromodiphenyl ether		mg/kg	5	n.d.	-
Dibromodiphenyl ether		mg/kg	5	n.d.	-
Tribromodiphenyl ether		mg/kg	5	n.d.	-
Tetrabromodiphenyl ether		mg/kg	5	n.d.	-
Pentabromodiphenyl ether		mg/kg	5	n.d.	-
Hexabromodiphenyl ether		mg/kg	5	n.d.	-
Heptabromodiphenyl ether		mg/kg	5	n.d.	-
Octabromodiphenyl ether		mg/kg	5	n.d.	-
Nonabromodiphenyl ether		mg/kg	5	n.d.	-
Decabromodiphenyl ether		mg/kg	5	n.d.	-
Sum of PBDEs		mg/kg	-	n.d.	1000

This document is issued by the Company subject to its General Conditions of Service printed overleaf, available on request or accessible at https://www.sgs.com.tw/terms-of-service and, for electronic format documents, subject to Terms and Conditions for Electronic Documents at https://www.sgs.com.tw/terms-of-service. Attention is drawn to the limitation of liability, indemnification and jurisdiction issues defined therein. Any holder of this document is advised that information contained hereon reflects the Company's findings at the time of its intervention only and within the limits of client's instruction, if any. The Company's sole responsibility is to its Client and this document does not exonerate parties to a transaction from exercising all their rights and obligations under the transaction documents. This document cannot be reproduced, except in full, without prior written approval of the Company. Any unauthorized alteration, forgery or falsification of the content or appearance of this document is unlawful and offenders may be prosecuted to the fullest extent of the law. Unless otherwise stated the results shown in this test report refer only to the sample(s) tested.

NXP SEMICONDUCTORS
HIGH TECH CAMPUS 60, 5656AG EINDHOVEN, THE NETHERLANDS

Test Item(s)	Method	Unit	MDL	Result No.1	Limit
Butyl benzyl phthalate (BBP)	With reference to IEC 62321-8: 2017, analysis was performed by GC/MS.	mg/kg	50	n.d.	1000
Dibutyl phthalate (DBP)	With reference to IEC 62321-8: 2017, analysis was performed by GC/MS.	mg/kg	50	n.d.	1000
Diisobutyl phthalate (DIBP)	With reference to IEC 62321-8: 2017, analysis was performed by GC/MS.	mg/kg	50	n.d.	1000
Di-(2-ethylhexyl) phthalate (DEHP)	With reference to IEC 62321-8: 2017, analysis was performed by GC/MS.	mg/kg	50	n.d.	1000
Diisononyl phthalate (DINP) (CAS No.: 28553-12-0, 68515-48-0)	With reference to IEC 62321-8: 2017, analysis was performed by GC/MS.	mg/kg	50	n.d.	-
Diisodecyl phthalate (DIDP) (CAS No.: 26761-40-0, 68515-49-1)	With reference to IEC 62321-8: 2017, analysis was performed by GC/MS.	mg/kg	50	n.d.	-
Di-n-octyl phthalate (DNOP) (CAS No.: 117-84-0)	With reference to IEC 62321-8: 2017, analysis was performed by GC/MS.	mg/kg	50	n.d.	-
Di-n-pentyl phthalate (DNPP) (CAS No.: 131-18-0)	With reference to IEC 62321-8: 2017, analysis was performed by GC/MS.	mg/kg	50	n.d.	-
Antimony (Sb) (CAS No.: 7440-36-0)	With reference to US EPA 3052: 1996, analysis was performed by ICP-OES.	mg/kg	2	n.d.	-
Beryllium (Be) (CAS No.: 7440-41-7)	With reference to US EPA 3052: 1996, analysis was performed by ICP-OES.	mg/kg	2	n.d.	-
Arsenic (As) (CAS No.: 7440-38-2)	With reference to US EPA 3052: 1996, analysis was performed by ICP-OES.	mg/kg	2	n.d.	-
Fluorine (F) (CAS No.: 14762-94-8)	With reference to BS EN 14582: 2016, analysis was performed by IC.	mg/kg	50	n.d.	-
Chlorine (Cl) (CAS No.: 22537-15-1)	With reference to BS EN 14582: 2016, analysis was performed by IC.	mg/kg	50	n.d.	-
Bromine (Br) (CAS No.: 10097-32-2)	With reference to BS EN 14582: 2016, analysis was performed by IC.	mg/kg	50	n.d.	-
Iodine (I) (CAS No.: 14362-44-8)	With reference to BS EN 14582: 2016, analysis was performed by IC.	mg/kg	50	n.d.	-

This document is issued by the Company subject to its General Conditions of Service printed overleaf, available on request or accessible at https://www.sgs.com.tw/terms-of-service and, for electronic format documents, subject to Terms and Conditions for Electronic Documents at https://www.sgs.com.tw/terms-of-service. Attention is drawn to the limitation of liability, indemnification and jurisdiction issues defined therein. Any holder of this document is advised that information contained hereon reflects the Company's findings at the time of its intervention only and within the limits of client's instruction, if any. The Company's sole responsibility is to its Client and this document does not exonerate parties to a transaction from exercising all their rights and obligations under the transaction documents. This document cannot be reproduced, except in full, without prior written approval of the Company. Any unauthorized alteration, forgery or falsification of the content or appearance of this document is unlawful and offenders may be prosecuted to the fullest extent of the law. Unless otherwise stated the results shown in this test report refer only to the sample(s) tested.

NXP SEMICONDUCTORS
HIGH TECH CAMPUS 60, 5656AG EINDHOVEN, THE NETHERLANDS

Note：

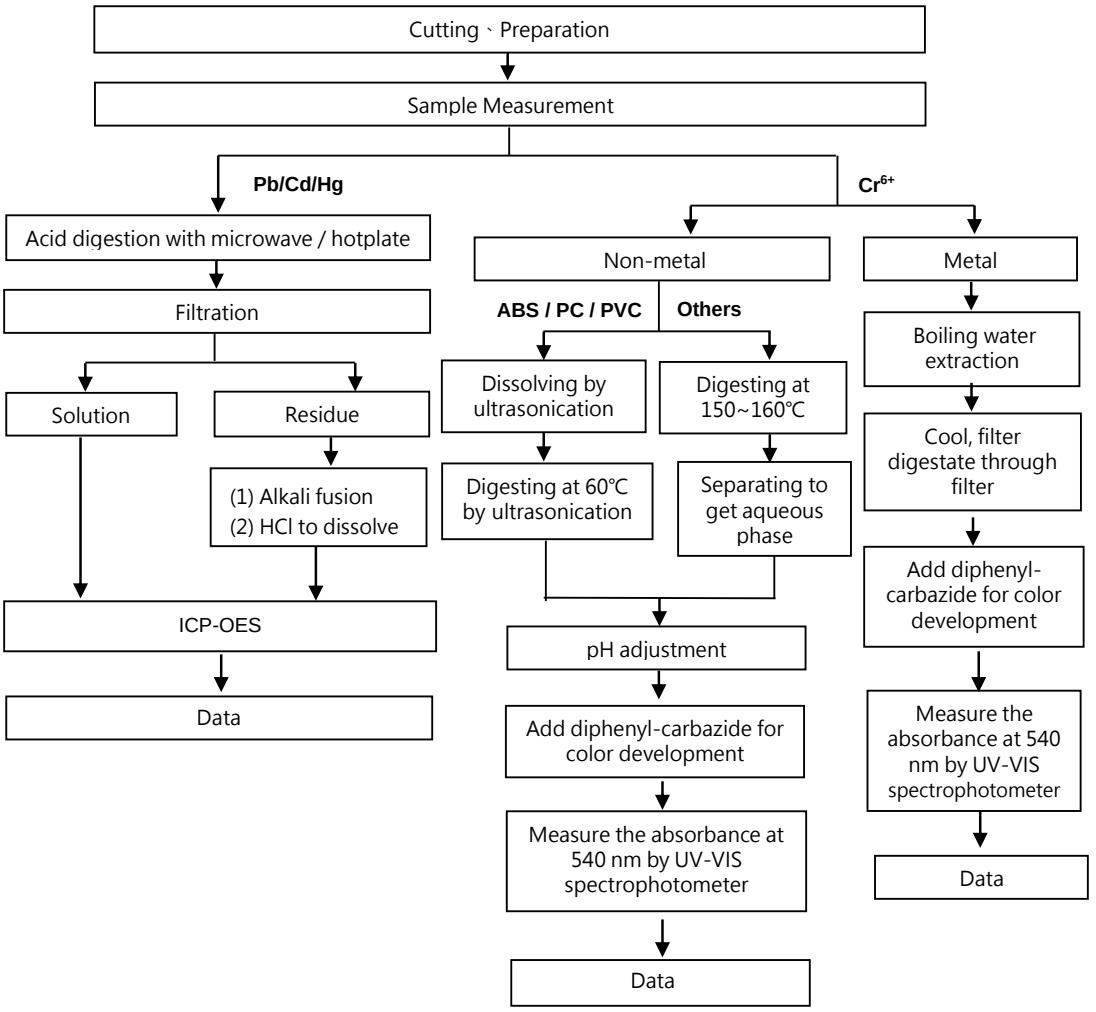
1. mg/kg = ppm ; 0.1wt% = 0.1% = 1000ppm
2. MDL = Method Detection Limit
3. n.d. = Not Detected (Less than MDL)
4. "-" = Not Regulated
5. Unless otherwise stated , the decision rule for conformity reporting is based on Binary Statement for Simple Acceptance Rule (w=0) stated in ILAC-G8:09/2019. According to this rule, the judgement of conformity is based on the comparing test results with limits.

This document is issued by the Company subject to its General Conditions of Service printed overleaf, available on request or accessible at https://www.sgs.com.tw/terms-of-service and, for electronic format documents, subject to Terms and Conditions for Electronic Documents at https://www.sgs.com.tw/terms-of-service. Attention is drawn to the limitation of liability, indemnification and jurisdiction issues defined therein. Any holder of this document is advised that information contained hereon reflects the Company's findings at the time of its intervention only and within the limits of client's instruction, if any. The Company's sole responsibility is to its Client and this document does not exonerate parties to a transaction from exercising all their rights and obligations under the transaction documents. This document cannot be reproduced, except in full, without prior written approval of the Company. Any unauthorized alteration, forgery or falsification of the content or appearance of this document is unlawful and offenders may be prosecuted to the fullest extent of the law. Unless otherwise stated the results shown in this test report refer only to the sample(s) tested.

NXP SEMICONDUCTORS
HIGH TECH CAMPUS 60, 5656AG EINDHOVEN, THE NETHERLANDS

Analytical flow chart of Heavy Metal

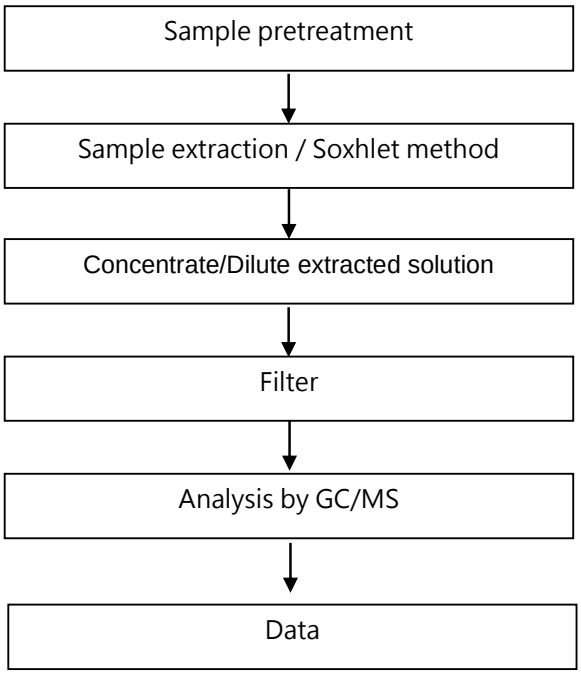
These samples were dissolved totally by pre-conditioning method according to below flow chart.
(Cr^{6+} test method excluded)



This document is issued by the Company subject to its General Conditions of Service printed overleaf, available on request or accessible at https://www.sgs.com.tw/terms-of-service and, for electronic format documents, subject to Terms and Conditions for Electronic Documents at https://www.sgs.com.tw/terms-of-service. Attention is drawn to the limitation of liability, indemnification and jurisdiction issues defined therein. Any holder of this document is advised that information contained hereon reflects the Company's findings at the time of its intervention only and within the limits of client's instruction, if any. The Company's sole responsibility is to its Client and this document does not exonerate parties to a transaction from exercising all their rights and obligations under the transaction documents. This document cannot be reproduced, except in full, without prior written approval of the Company. Any unauthorized alteration, forgery or falsification of the content or appearance of this document is unlawful and offenders may be prosecuted to the fullest extent of the law. Unless otherwise stated the results shown in this test report refer only to the sample(s) tested.

NXP SEMICONDUCTORS
HIGH TECH CAMPUS 60, 5656AG EINDHOVEN, THE NETHERLANDS

PBB/PBDE analytical FLOW CHART

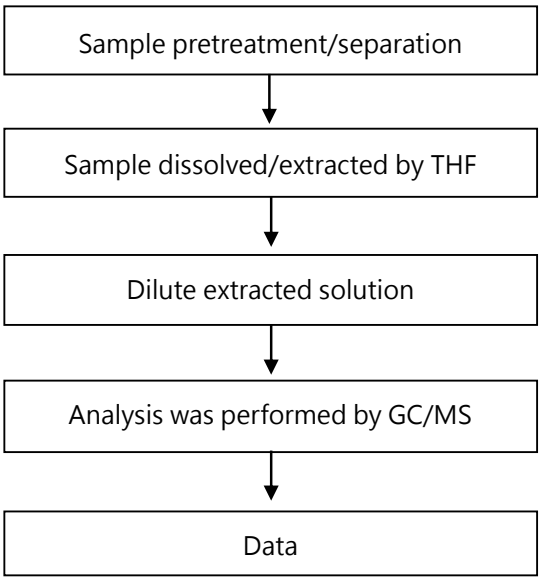


This document is issued by the Company subject to its General Conditions of Service printed overleaf, available on request or accessible at https://www.sgs.com.tw/terms-of-service and, for electronic format documents, subject to Terms and Conditions for Electronic Documents at https://www.sgs.com.tw/terms-of-service. Attention is drawn to the limitation of liability, indemnification and jurisdiction issues defined therein. Any holder of this document is advised that information contained hereon reflects the Company's findings at the time of its intervention only and within the limits of client's instruction, if any. The Company's sole responsibility is to its Client and this document does not exonerate parties to a transaction from exercising all their rights and obligations under the transaction documents. This document cannot be reproduced, except in full, without prior written approval of the Company. Any unauthorized alteration, forgery or falsification of the content or appearance of this document is unlawful and offenders may be prosecuted to the fullest extent of the law. Unless otherwise stated the results shown in this test report refer only to the sample(s) tested.

NXP SEMICONDUCTORS
HIGH TECH CAMPUS 60, 5656AG EINDHOVEN, THE NETHERLANDS

Analytical flow chart of phthalate content

【Test method: IEC 62321-8】



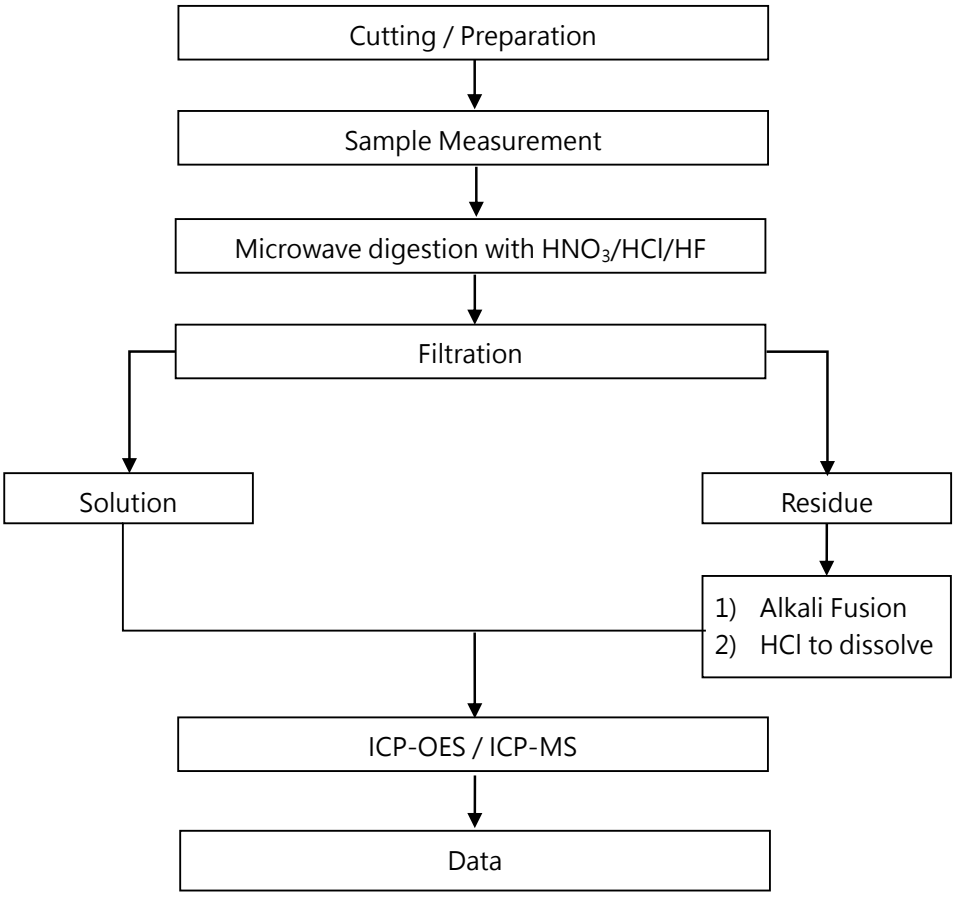
This document is issued by the Company subject to its General Conditions of Service printed overleaf, available on request or accessible at https://www.sgs.com.tw/terms-of-service and, for electronic format documents, subject to Terms and Conditions for Electronic Documents at https://www.sgs.com.tw/terms-of-service. Attention is drawn to the limitation of liability, indemnification and jurisdiction issues defined therein. Any holder of this document is advised that information contained hereon reflects the Company's findings at the time of its intervention only and within the limits of client's instruction, if any. The Company's sole responsibility is to its Client and this document does not exonerate parties to a transaction from exercising all their rights and obligations under the transaction documents. This document cannot be reproduced, except in full, without prior written approval of the Company. Any unauthorized alteration, forgery or falsification of the content or appearance of this document is unlawful and offenders may be prosecuted to the fullest extent of the law. Unless otherwise stated the results shown in this test report refer only to the sample(s) tested.

NXP SEMICONDUCTORS
HIGH TECH CAMPUS 60, 5656AG EINDHOVEN, THE NETHERLANDS

Analytical flow chart of Elements (Heavy metal included)

These samples were dissolved totally by pre-conditioning method according to below flow chart.

【Reference method：US EPA 3051、US EPA 3052】

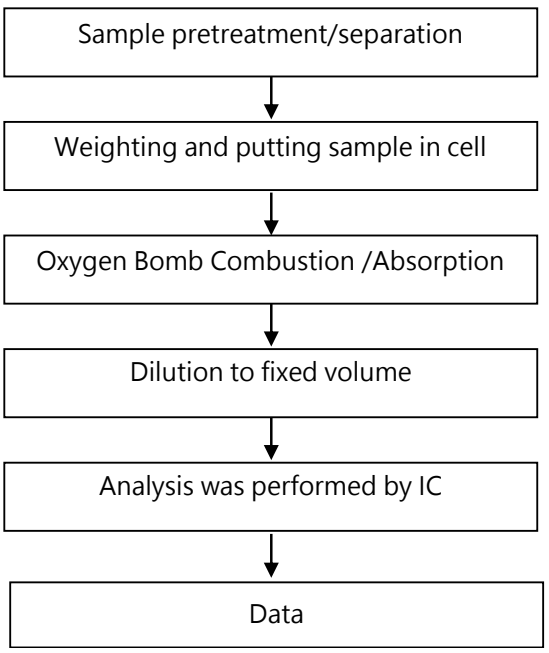


* US EPA 3051 method does not add HF.

This document is issued by the Company subject to its General Conditions of Service printed overleaf, available on request or accessible at https://www.sgs.com.tw/terms-of-service and, for electronic format documents, subject to Terms and Conditions for Electronic Documents at https://www.sgs.com.tw/terms-of-service. Attention is drawn to the limitation of liability, indemnification and jurisdiction issues defined therein. Any holder of this document is advised that information contained hereon reflects the Company's findings at the time of its intervention only and within the limits of client's instruction, if any. The Company's sole responsibility is to its Client and this document does not exonerate parties to a transaction from exercising all their rights and obligations under the transaction documents. This document cannot be reproduced, except in full, without prior written approval of the Company. Any unauthorized alteration, forgery or falsification of the content or appearance of this document is unlawful and offenders may be prosecuted to the fullest extent of the law. Unless otherwise stated the results shown in this test report refer only to the sample(s) tested.

NXP SEMICONDUCTORS
HIGH TECH CAMPUS 60, 5656AG EINDHOVEN, THE NETHERLANDS

Analytical flow chart of Halogen

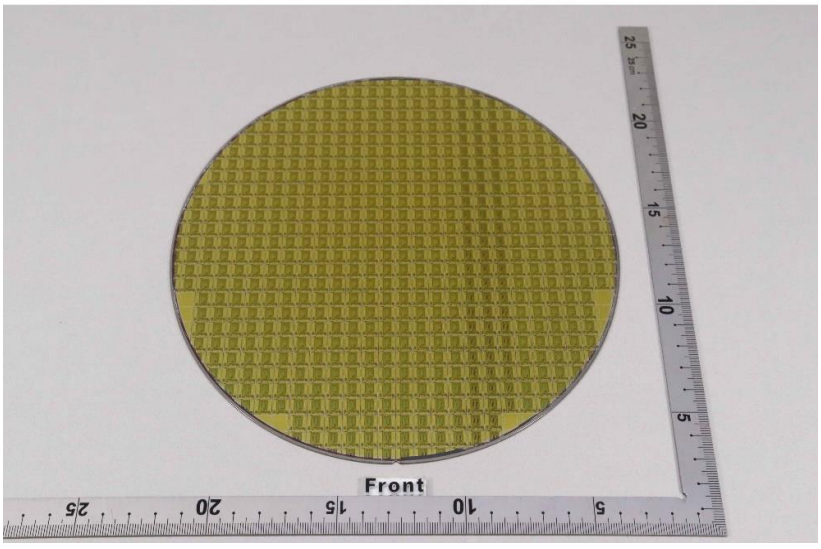


This document is issued by the Company subject to its General Conditions of Service printed overleaf, available on request or accessible at https://www.sgs.com.tw/terms-of-service and, for electronic format documents, subject to Terms and Conditions for Electronic Documents at https://www.sgs.com.tw/terms-of-service. Attention is drawn to the limitation of liability, indemnification and jurisdiction issues defined therein. Any holder of this document is advised that information contained hereon reflects the Company's findings at the time of its intervention only and within the limits of client's instruction, if any. The Company's sole responsibility is to its Client and this document does not exonerate parties to a transaction from exercising all their rights and obligations under the transaction documents. This document cannot be reproduced, except in full, without prior written approval of the Company. Any unauthorized alteration, forgery or falsification of the content or appearance of this document is unlawful and offenders may be prosecuted to the fullest extent of the law. Unless otherwise stated the results shown in this test report refer only to the sample(s) tested.

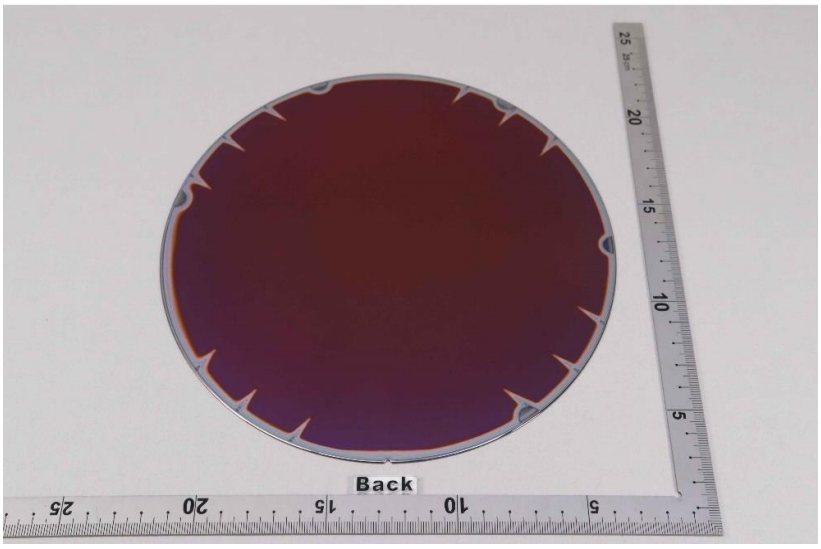
NXP SEMICONDUCTORS
HIGH TECH CAMPUS 60, 5656AG EINDHOVEN, THE NETHERLANDS

*** The tested sample / part is marked by an arrow if it's shown on the photo. ***

EKR24600524



EKR24600524



** End of Report **

This document is issued by the Company subject to its General Conditions of Service printed overleaf, available on request or accessible at https://www.sgs.com.tw/terms-of-service and, for electronic format documents, subject to Terms and Conditions for Electronic Documents at https://www.sgs.com.tw/terms-of-service. Attention is drawn to the limitation of liability, indemnification and jurisdiction issues defined therein. Any holder of this document is advised that information contained hereon reflects the Company's findings at the time of its intervention only and within the limits of client's instruction, if any. The Company's sole responsibility is to its Client and this document does not exonerate parties to a transaction from exercising all their rights and obligations under the transaction documents. This document cannot be reproduced, except in full, without prior written approval of the Company. Any unauthorized alteration, forgery or falsification of the content or appearance of this document is unlawful and offenders may be prosecuted to the fullest extent of the law. Unless otherwise stated the results shown in this test report refer only to the sample(s) tested.